Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination CHEN, HON-LUN Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,234,737 A	08-1993	Ueno et al.	428/64.4
*	В	US-6,042,921 A	03-2000	Yoshinari et al.	428/64.1
*	С	US-6,064,642 A	05-2000	Okubo, Shuichi	369/275.1
*	D	US-6,240,060 B1	05-2001	Kikitsu et al.	369/275.1
*	E	US-6,231,945 B1	05-2001	Miyamoto et al.	428/64.1
*	F	US-2001/0055268 A1	12-2001	Okubo, Shuichi	369/275.2
*	G	US-2004/0076908 A1	04-2004	Oomachi et al.	430/270.13
	Н	US-			
	-	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

		NON FACEUR DOCUMENTS
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	x	

^{*}A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.